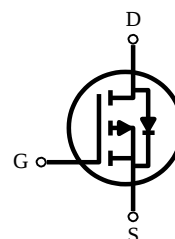
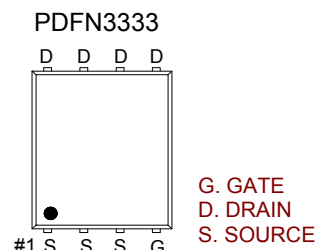


P-Channel High Density Trench MOSFET

FEATURES

- Super high dense cell trench design for low RDS(on).
- Rugged and reliable.
- Surface Mount package.

PRODUCT SUMMARY		
$V_{(BR)DSS}$	$R_{DS(on)} (m\Omega) \text{ Max}$	I_D
-30V	12 @ $V_{GS} = -10V$	-38A
	16 @ $V_{GS} = -4.5V$	



ABSOLUTE MAXIMUM RATINGS (TA = 25 °C unless otherwise noted)

Parameter		Symbol	Limit	Unit
Drain-Source Voltage		V _{DS}	-30	V
Gate-Source Voltage		V _{GS}	±25	V
Drain Current-Continuous	TC=25℃	I _D	-42	A
	TC=70℃		-28.5	
Pulsed Drain Current (Note 1)		I _{DM}	-120	
Avalanche Current		I _{AS}	-38	
Single Pulse Avalanche Energy	L = 0.1mH	E _{AS}	70	mJ
Maximum Power Dissipation (Note 1)	TA=25℃	P _D	4.1	W
	TA=70℃		2.6	
Operating Junction and Storage Temperature Range		T _J ,T _{STG}	- 55 to 150	℃

TYPICAL THERMAL CHARACTERISTICS (Note 1)

Thermal Resistance, Junction-to-Case	R_{thJC}	2.5	°C/W
Thermal Resistance Junction-Ambient	R_{thJA}	62.5	°C/W

Note :

1. Pulse width limited by maximum junction temperature.

P-Channel High Density Trench MOSFET

ELECTRICAL CHARACTERISTICS (TA = 25 °C unless otherwise noted)

Parameter	Symbol	Condition	Min	Typ	Max	Unit
OFF CHARACTERISTICS						
Drain-Source Breakdown Voltage	BV _{DSS}	V _{GS} = 0V , I _D = -250uA	-30			V
Zero Gate Voltage Drain Current	I _{DSS}	V _{DS} = -24V , V _{GS} = 0V, T _j = 25°C			-1	uA
		V _{DS} = -24V , V _{GS} = 0V , T _j = 125°C			-30	
Gate-Body Leakage	I _{GSS}	V _{GS} = ±25V , V _{DS} = 0V			±100	nA
ON CHARACTERISTICS (Note 2)						
Gate Threshold Voltage	V _{GS(th)}	V _{DS} = VGS , I _D = 250uA	-1	-1.4	-2.5	V
Drain-Source On-State Resistance	R _{DS(on)}	V _{GS} = -10V , I _D = -12A		7.4	12	mΩ
		V _{GS} = -4.5V , I _D = -9A		9.8	16	mΩ
Forward Transconductance	g _{fs}	V _{DS} = -10V , I _D = -12A		16		S
DYNAMIC CHARACTERISTICS						
Input Capacitance	C _{ISS}	V _{DS} = -15V , V _{GS} = 0V f = 1.0MHz		2078		pF
Output Capacitance	C _{OSS}			203		pF
Reverse Transfer Capacitance	C _{RSS}			185		pF
Gate Resisance	R _g	V _{DS} = 0V , V _{GS} = 0V , f = 1.0MHz		6		Ω
SWITCHING CHARACTERISTICS (Note 3)						
Turn-On Delay Time	td _(ON)	V _{DD} = -15V , I _D = -1A , V _{GS} = -10V R _{GS} = 6 Ω		12.8		nS
Rise Time	tr			24.2		nS
Turn-Off Delay Time	td _(OFF)			72		nS
Fall Time	tf			33.1		nS
Total Gate Charge (10V)	Qg	V _{DS} = -15BVDSS , I _D = -12A V _{GS} = -10V		42		nC
Total Gate Charge (4.5V)	Qg			26.3		nC
Gate-Source Charge	Qgs			6.7		nC
Gate-Drain Charge	Qgd			8.5		nC
DRAIN-SOURCE DIODE CHARACTERISTICS						
Continuous Current	I _s				-30	A
Diode Forward Voltage (Note 2)	V _{SD}	V _{GS} = 0V , I _S = I _F		-0.75	-1.2	V

Note :

2. Pulse Test Pulse width ≤ 300uSec , Duty Cycle ≤ 2%
3. Independent of operating production testing .

P-Channel High Density Trench MOSFET

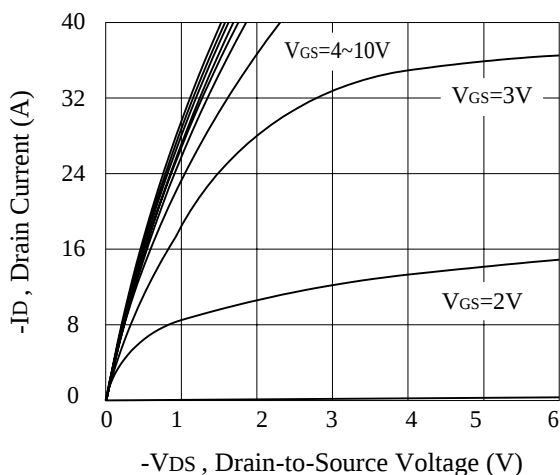


Figure 1. Output Characteristics

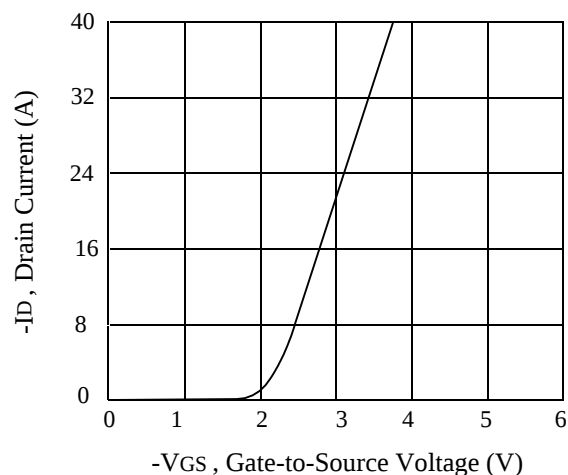


Figure 2. Transfer Characteristics

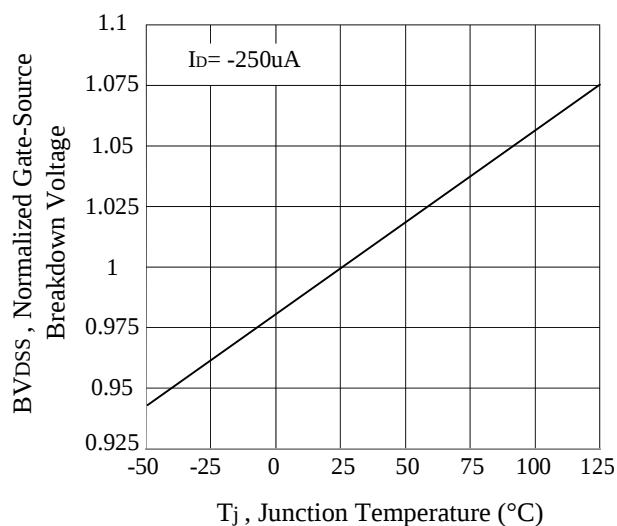


Figure 3. Breakdown Voltage Variation with Temperature

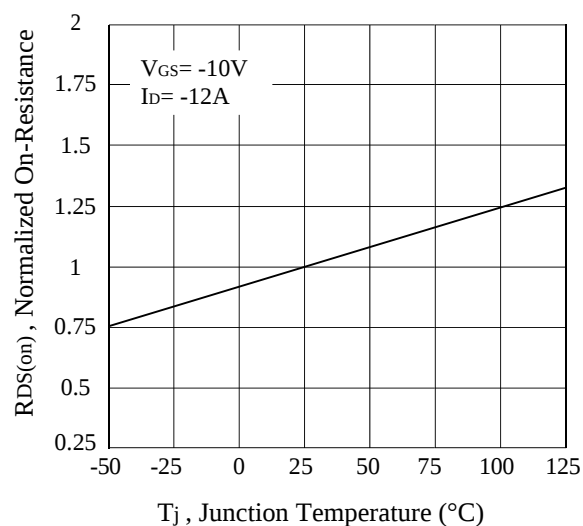


Figure 4. On-Resistance Variation with Temperature

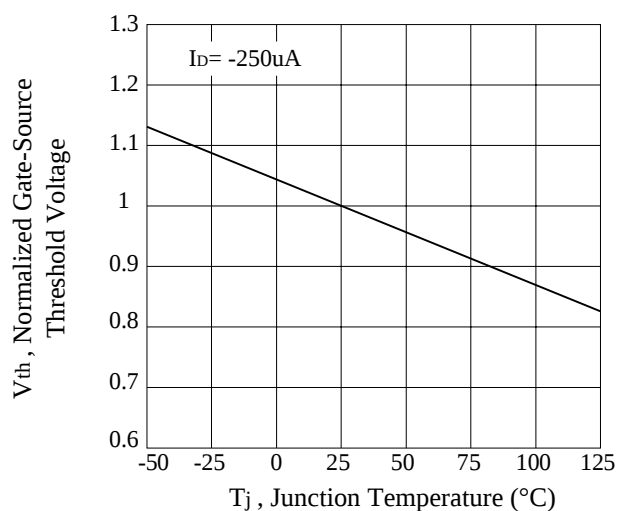


Figure 5. Gate Threshold Variation with Temperature

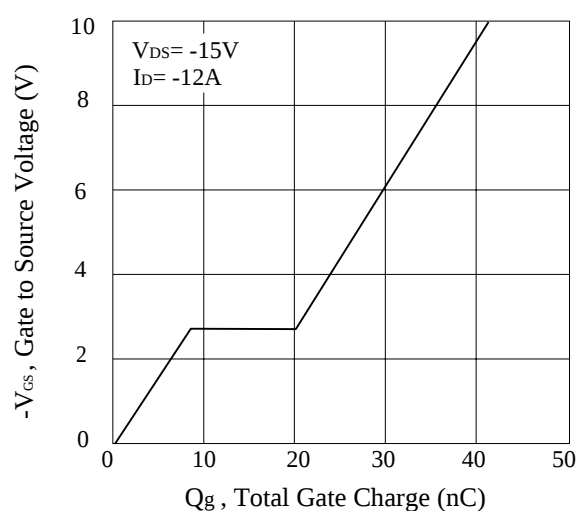
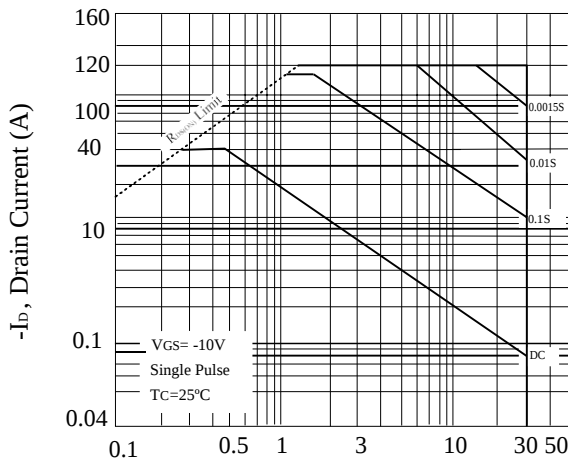
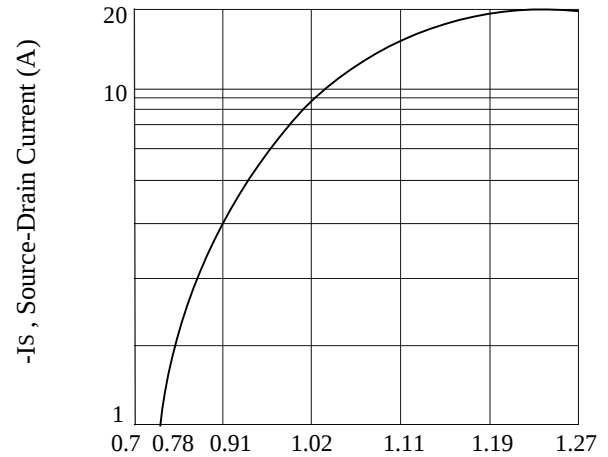


Figure 6. Gate Charge

P-Channel High Density Trench MOSFET



-VDS, Drain-Source Voltage (V)
 Figure 7. Maximum Safe Operating Area



-VSD, Body Diode Forward Voltage (V)
 Figure 8. Body Diode Forward Voltage Variation with Source Current

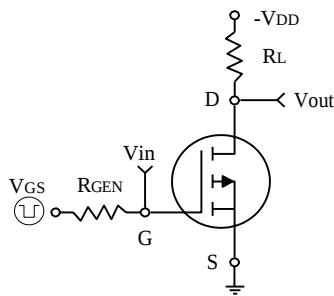


Figure 9. Switching Test Circuit and Switching Waveforms

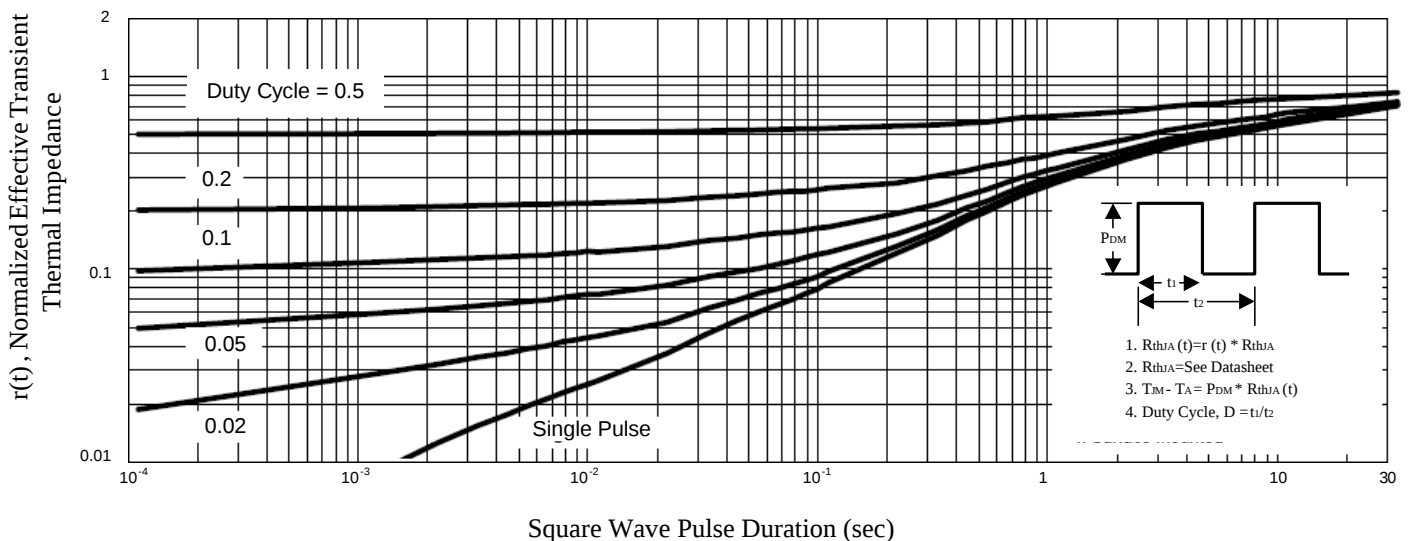


Figure 10. Normalized Thermal Transient Impedance Curve